

**Amendments to the Claims:**

This listing of claims will replace all prior versions, and listings, of claims in the application:

**Listing of Claims:**

1. (Currently Amended) A method for testing a physical layer device including a link layer interface, a physical layer logic circuit to be connected to said link layer interface, and a plurality of ports to be connected to said physical layer logic circuit are provided beforehand in said physical layer device;

in testing, said test link layer circuit is connected to said physical layer logic circuit through said link layer interface, and said test physical layer logic circuit is connected to a first port that is one of said plurality of ports, and said first port is connected to a second port that is one of said plurality of ports through an external bus, and the second port is connected to said physical layer logic circuit; and

said link layer interface, said physical layer logic circuit, and said plurality of ports are tested.

2. (Currently Amended): A physical layer device with test circuits, said physical layer device including a link layer interface, a physical layer logic circuit to be connected to said link layer interface, and a plurality of ports to be connected to said physical layer logic circuit, said physical layer device characterized by ~~comprising~~ comprising:

a test link layer circuit for establishing,[[,]] in testing, a connection with said link layer interface, a connection with said physical layer logic circuit through said link layer interface and communicating predetermined data with said physical layer logic circuit; and

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a test physical layer logic circuit for establishing, in testing, a connection with said plurality of ports, wherein a first port that is one of said plurality of ports, is connected to a second port that is one of said plurality of ports through an external bus, ~~where~~ and the ~~first and~~ second ports are connected to ~~a connection~~ with said physical layer logic circuit ~~through said plurality of ports~~ and communicating predetermined data with said physical layer logic circuit.

3. (Original) A physical layer device with test circuits according to claim 2, characterized in that:

said link layer interface includes a switch for selectively establishing a connection with an external link layer device or said test link layer circuit; and  
a predetermined port from among said plurality of ports includes a switch for selectively establishing a connection with said physical layer logic circuit or said test physical layer logic circuit.

4-13. (Canceled)